



HIGH SPEED, TRIPLE DIGITAL ISOLATORS

Check for Samples: ISO7230C, ISO7230M, ISO7231C, ISO7231M

FEATURES

- 25 and 150-Mbps Signaling Rate Options
 - Low Channel-to-Channel Output Skew;
 1 ns max
 - Low Pulse-Width Distortion (PWD);2 ns max
 - Low Jitter Content; 1 ns Typ at 150 Mbps
- Typical 25-Year Life at Rated Working Voltage (See Application Note SLLA197 and Figure 14)
- 4000-V_{peak} Isolation, 560-V_{peak} V_{IORM}
 - UL 1577, IEC 60747-5-2 (VDE 0884, Rev 2),
 IE 61010-1, IEC 60950-1 and CSA Approved
- 4 kV ESD Protection
- Operate With 3.3-V or 5-V Supplies

- High Electromagnetic Immunity (See Application Note SLLA181)
- –40°C to 125°C Operating Range

APPLICATIONS

- Industrial Fieldbus
- Computer Peripheral Interface
- Servo Control Interface
- Data Acquisition

DESCRIPTION

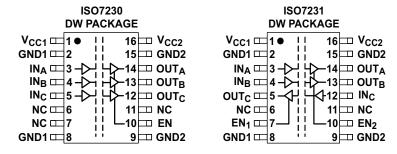
The ISO7230 and ISO7231 are triple-channel digital isolators each with multiple channel configurations and output enable functions. These devices have logic input and output buffers separated by Tl's silicon dioxide (SiO₂) isolation barrier. Used in conjunction with isolated power supplies, these devices block high voltage, isolate grounds, and prevent noise currents on a data bus or other circuits from entering the local ground and interfering with or damaging sensitive circuitry.

The ISO7230 triple-channel device has all three channels in the same direction while the ISO7231 has two channels in one direction and one channel in opposition. These devices have an active-high output enable that when driven to a low level, places the output in a high-impedance state.

The ISO7230C and ISO7231C have TTL input thresholds and a noise-filter at the input that prevents transient pulses of up to 2 ns in duration from being passed to the output of the device, while the ISO7230M and ISO7231M have CMOS $V_{\rm CC}/2$ input thresholds and do not have the input noise-filter or the additional propagation delay.

In each device, a periodic update pulse is sent across the isolation barrier to ensure the proper dc level of the output. If this dc-refresh pulse is not received, the input is assumed to be unpowered or not being actively driven, and the failsafe circuit drives the output to a logic high state. (Contact TI for a logic low failsafe option).

These devices require two supply voltages of 3.3-V, 5-V, or any combination. All inputs are 5-V tolerant when supplied from a 3.3-V supply and all outputs are 4-mA CMOS. These devices are characterized for operation over the ambient temperature range of -40°C to 125°C.





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.





These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

FUNCTION DIAGRAM

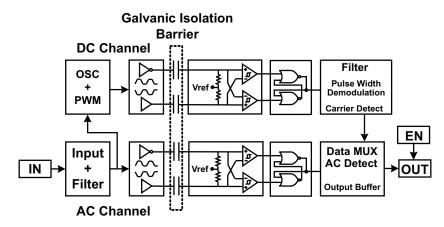


Table 1. Device Function Table ISO723x (1)

INPUT V _{CC}	OUTPUT V _{CC}	INPUT OUTPUT ENABLE (IN) (EN)		OUTPUT (OUT)
		Н	H or Open	Н
DU	DII	L	H or Open	L
PU	PU	Х	L	Z
		Open	H or Open	Н
PD	PU	PU X H or Ope		Н
PD	PU	Х	L	Z

(1) PU = Powered Up; PD = Powered Down; X = Irrelevant; H = High Level; L = Low Level

AVAILABLE OPTIONS

PRODUCT	SIGNALING RATE	INPUT THRESHOLD	CHANNEL CONFIGURATION	MARKED AS	ORDERING NUMBER ⁽¹⁾
ISO7230CDW	25 Mbps	~1.5 V (TTL)		ISO7230C	ISO7230CDW (rail)
1307230CDW	25 Mibbs	(CMOS compatible)	3/0	13072300	ISO7230CDWR (reel)
ISO7230MDW	150 Mbpo	\/aa/2 (CMOS)	3/0	ISO7230M	ISO7230MDW (rail)
1507230IVIDVV	150 Mbps	Vcc/2 (CMOS)		1507230101	ISO7230MDWR (reel)
1007004 CDW	OF Mhan	~1.5 V (TTL)		10070040	ISO7231CDW (rail)
ISO7231CDW	25 Mbps	(CMOS compatible)	0/4	ISO7231C	ISO7231CDWR (reel)
ICO7224MDW	150 Mbps	Ves/2 (CMOC)	2/1	ICO7224M	ISO7231MDW (rail)
ISO7231MDW	150 Mbps	Vcc/2 (CMOS)		ISO7231M	ISO7231MDWR (reel)

(1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.



ABSOLUTE MAXIMUM RATINGS(1)

					VALUE	UNIT
V_{CC}	Supply voltage	je ⁽²⁾ , V _{CC1} , V _{CC2}			-0.5 to 6	V
V_{I}	Voltage at IN	, OUT, EN			-0.5 to 6	V
Io	Output currer	Output current				mA
		Human Body Model	JEDEC Standard 22, Test Method A114-C.01		±4	
ESD	Electrostatic discharge	Field-Induced-Charged Device Model	JEDEC Standard 22, Test Method C101	All pins	±1	kV
		Machine Model	ANSI/ESDS5.2-1996		±200	V
TJ	Maximum jun		170	°C		

Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

RECOMMENDED OPERATING CONDITIONS

			MIN	TYP	MAX	UNIT
V_{CC}	Supply voltage ⁽¹⁾ , V _{CC1} , V _{CC2}		3.15		5.5	V
I _{OH}	High-level output current		-4			mA
I _{OL}	Low-level output current				4	mA
	lament made a scientin	ISO723xC	40			
t _{ui}	Input pulse width	ISO723xM	6.67	5		ns
4 /1	O'avad'a varia	ISO723xC	0	30 ⁽²⁾	25	N 41
1/t _{ui}	_{ui} Signaling rate	ISO723xM	0	200(2)	150	Mbps
V_{IH}	High-level input voltage (IN)	100700.14	0.7 V _{CC}		V _{CC}	
V_{IL}	Low-level input voltage (IN)	ISO723xM	0		0.3 V _{CC}	V
V_{IH}	High-level input voltage (IN) (EN on all devices)	100700.0	2		V _{CC}	
V_{IL}	Low-level input voltage (IN) (EN on all devices)	ISO723xC	0		0.8	V
T_{J}	Junction temperature				150	°C
Н	External magnetic field-strength immunity per IEC certification	C 61000-4-8 and IEC 61000-4-9			1000	A/m

For the 5-V operation, V_{CC1} or V_{CC2} is specified from 4.5 V to 5.5 V. For the 3-V operation, V_{CC1} or V_{CC2} is specified from 3.15 V to 3.6 V. Typical sigalling rate under ideal conditions at 25°C.

All voltage values are with respect to network ground terminal and are peak voltage values.



ELECTRICAL CHARACTERISTICS: V_{CC1} and V_{CC2} at 5-V $^{(1)}$ OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
SUPPLY	CURRENT						
	ISO7230C/M	Quiescent	V _I = V _{CC} or 0 V, All channels, no load,		1	3	A
	1507230C/W	25 Mbps	EN ₂ at 3 V		7	9.5	mA
I _{CC1}	10070040/M	Quiescent	V _I = V _{CC} or 0 V, All channels, no load,		6.5	11	A
	ISO7231C/M	25 Mbps	EN ₁ at 3 V, EN ₂ at 3 V		11	17	mA
	ISO7230C/M	Quiescent	V _I = V _{CC} or 0 V, All channels, no load,		15	22	A
	1507230C/M	25 Mbps	EN ₂ at 3 V		17	24	mA
I _{CC2}	10070040/M	Quiescent	V _I = V _{CC} or 0 V, All channels, no load,		13	20	A
	ISO7231C/M	25 Mbps	EN ₁ at 3 V, EN ₂ at 3 V		17.5	27	mA
ELECTR	RICAL CHARACTERISTI	cs					
I _{OFF}	Sleep mode output cu	ırrent	EN at 0 V, Single channel		0		μΑ
V	High-level output volta	200	I _{OH} = -4 mA, See Figure 1	V _{CC} - 0.8			V
V _{OH}	High-level output voita	age	$I_{OH} = -20 \mu A$, See Figure 1	V _{CC} - 0.1	V _{CC} – 0.1		V
V	Low-level output volta	30	I _{OL} = 4 mA, See Figure 1			0.4	V
V_{OL}	Low-level output volta	ge	I_{OL} = 20 μ A, See Figure 1			0.1	V
$V_{I(HYS)}$	Input voltage hysteres	sis			150		mV
I _{IH}	High-level input currer	nt	IN from 0 V/ to V/			10	^
I _{IL}	Low-level input curren	nt	IN from 0 V to V _{CC}	-10			μА
Cı	Input capacitance to g	ground	IN at V_{CC} , $V_{I} = 0.4 \sin (4E6\pi t)$		2		pF
CMTI	Common-mode transi	ent immunity	V _I = V _{CC} or 0 V, See Figure 4	25	50		kV/μs

⁽¹⁾ For the 5-V operation, V_{CC1} or V_{CC2} is specified from 4.5 V to 5.5 V. For the 3-V operation, V_{CC1} or V_{CC2} is specified from 3.15 V to 3.6 V.



SWITCHING CHARACTERISTICS: V_{CC1} and V_{CC2} at 5-V OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH} , t _{PHL}	Propagation delay	10072240	See Figure 4	18		42	20
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} - t _{PLH}	ISO723xC	See Figure 1			2.5	ns
t _{PLH} , t _{PHL}	Propagation delay	ICO702M		10		23	
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} - t _{PLH}	ISO723xM			1	2	ns
	Don't to nort allow (2)	ISO723xC				8	
t _{sk(pp)}	Part-to-part skew (2)	ISO723xM		0 3		ns	
	Channel to sharped output along (3)	ISO723xC			0	2	
t _{sk(o)}	Channel-to-channel output skew (3)	ISO723xM			0	1	ns
t _r	Output signal rise time		0		2		
t _f	Output signal fall time		See Figure 1		2		ns
t _{PHZ}	Propagation delay, high-level-to-high-in	npedance output			15	20	
t _{PZH}	Propagation delay, high-impedance-to-	high-level output	Saa Figure 2		15	20	
t _{PLZ}	Propagation delay, low-level-to-high-im	pedance output	See Figure 2		15	20	ns
t _{PZL}	Propagation delay, high-impedance-to-low-level output				15	20	
t _{fs}	Failsafe output delay time from input power loss		See Figure 3		12		μS
t _{jit(pp)}	Peak-to-peak eye-pattern jitter	ISO723xM	150 Mbps PRBS NRZ data input, Same polarity inputon all channels, See Figure 5		1		ns

⁽¹⁾ Also referred to as pulse skew.

⁽²⁾ t_{sk(pp)} is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

⁽³⁾ $t_{sk(0)}$ is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.



ELECTRICAL CHARACTERISTICS: V_{CC1} at 5-V, V_{CC2} at 3.3-V⁽¹⁾ OPERATION

	PARAMETE	R	TEST CONDITION	IS	MIN	TYP	MAX	UNIT
SUPPLY	CURRENT							
	ISO7230C/M	Quiescent	$V_{I} = V_{CC}$ or 0 V, All channels, no lo	and EN at 2 V		1	3	mA
	1507230C/W	25 Mbps	$V_1 = V_{CC}$ or 0 V, All channels, no ic	bau, EN ₂ at 3 v		7	9.5	MA
I _{CC1}	ISO7231C/M	Quiescent	$V_I = V_{CC}$ or 0 V, All channels, no lo	oad, EN ₁ at 3 V,		6.5	11	mA
	1507231C/W	25 Mbps	EN ₂ at 3 V	· · · · · ·		11	17	mA
	ISO7230C/M	Quiescent	V - V or 0 V All channels no la	and EN at 2 V		9	15	mA
	1307230C/W	25 Mbps	$V_I = V_{CC}$ or 0 V, All channels, no lo	Jau, EN ₂ at 3 V		10	17	ША
I _{CC2}	ISO7231C/M	Quiescent	$V_I = V_{CC}$ or 0 V, All channels, no lo	oad, EN₁ at 3 V,		8	12	mA
	1507231C/W	25 Mbps	EN ₂ at 3 V	•		10.5	16	mA
ELECTR	ICAL CHARACTE	RISTICS						
I _{OFF}	Sleep mode outp	out current	EN at 0 V, Single channel		0		μΑ	
			ISO7		V _{CC} - 0.4			
V_{OH}	High-level output	t voltage		ISO7231 (5-V side)	V _{CC} - 0.8			V
			I _{OH} = -20 μA, See Figure 1		V _{CC} - 0.1			
	l avvilaval avviavit		I _{OL} = 4 mA, See Figure 1				0.4	V
V_{OL}	Low-level output	voitage	I _{OL} = 20 μA, See Figure 1				0.1	V
V _{I(HYS)}	Input voltage hys	steresis				150		mV
I _{IH}	High-level input	current	IN Green O.V. (a.V.				10	^
I _{IL}	Low-level input of	current	IN from 0 V to V _{CC}		-10			μΑ
C _I	Input capacitanc	e to ground	IN at V_{CC} , $V_{I} = 0.4 \sin (4E6\pi t)$	IN at V_{CC} , $V_{I} = 0.4 \sin (4E6\pi t)$		2		pF
CMTI	Common-mode to immunity	transient	V _I = V _{CC} or 0 V, See Figure 4		25	50		kV/μs

⁽¹⁾ For the 5-V operation, V_{CC1} or V_{CC2} is specified from 4.5 V to 5.5 V. For the 3-V operation, V_{CC1} or V_{CC2} is specified from 3.15 V to 3.6 V.



SWITCHING CHARACTERISTICS: V_{CC1} at 5-V, V_{CC2} at 3.3-V OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH} , t _{PHL}	Propagation delay, low-to-high-level output	1007000	Con Figure 4	20		50	
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} - t _{PLH}	ISO723xC	See Figure 1			3	ns
t _{PLH} , t _{PHL}	Propagation delay, low-to-high-level output	100700М		12		29	
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} - t _{PLH}	ISO723xM			1	2	ns
	Dom'to and class (2)	ISO723xC			10		
t _{sk(pp)}	Part-to-part skew ⁽²⁾	ISO723xM			0	5	ns
	Channel to all and a land (3)	ISO723xC			0	2.5	
t _{sk(o)}	Channel-to-channel output skew (3)	ISO723xM			0	1	ns
t _r	Output signal rise time		Con Figure 4		2		
t _f	Output signal fall time		See Figure 1		2		ns
t _{PHZ}	Propagation delay, high-level-to-high-impeda	nce output			15	20	
t _{PZH}	Propagation delay, high-impedance-to-high-le	evel output	Con Figure 0		15	20	
t _{PLZ}	Propagation delay, low-level-to-high-impedan	ice output	See Figure 2		15	20	ns
t _{PZL}	Propagation delay, high-impedance-to-low-le	vel output			15	20	
t _{fs}	Failsafe output delay time from input power loss		See Figure 3		18		μS
t _{jit(pp)}	Peak-to-peak eye-pattern jitter	ISO723xM	150 Mbps PRBS NRZ data input, Same polarity input on all channels, See Figure 5		1		ns

Also known as pulse skew (1)

 $t_{sk(pp)}$ is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits. $t_{sk(0)}$ is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the

same direction while driving identical specified loads.



ELECTRICAL CHARACTERISTICS: V_{CC1} at 3.3-V, V_{CC2} at 5-V⁽¹⁾ OPERATION

	PARAMETE	:R	TEST CONDITION	S	MIN	TYP	MAX	UNIT
SUPPLY	CURRENT							
	ISO7230C/M	Quiescent	// // or 0 // All channels no la	and FN at 2 V		0.5	1	mA
	1507230C/M	25 Mbps	$V_I = V_{CC}$ or 0 V, All channels, no lo	au, ⊑in ₂ at 3 v		3	5	MA
I _{CC1}	ISO7231C/M	Quiescent	$V_I = V_{CC}$ or 0 V, All channels, no lo	oad, EN ₁ at 3 V,		4.5	7	mA
	13072310/101	25 Mbps	EN ₂ at 3 V		6.5	11	ША	
	ISO7230C/M	Quiescent	$V_I = V_{CC}$ or 0 V, All channels, no lo	and EN at 3 V		15	22	mA
	1307230C/W	25 Mbps	VI = VCC OI O V, All Charmers, no ic	au, Lin ₂ at 5 v		17	24	ША
I _{CC2}	ISO7231C/M	Quiescent	$V_I = V_{CC}$ or 0 V, All channels, no lo	oad, EN ₁ at 3 V,		13	20	mA
	13072310/101	25 Mbps	EN ₂ at 3 V			17.5	27	ША
ELECTR	ICAL CHARACTE	RISTICS						
I _{OFF}	Sleep mode outp	out current	EN at 0 V, Single channel			0		μΑ
			$I_{OH} = -4$ mA, See Figure 1	ISO7230	V _{CC} - 0.4			
V_{OH}	High-level outpu			ISO7231 (5-V side)	V _{CC} - 0.8			V
			$I_{OH} = -20 \mu A$, See Figure 1		V _{CC} - 0.1			
V	Low lovel output	voltogo	I _{OL} = 4 mA, See Figure 1				0.4	V
V _{OL}	Low-level output	voltage	I _{OL} = 20 μA, See Figure 1				0.1	V
$V_{I(HYS)}$	Input voltage hys	steresis				150		mV
I _{IH}	High-level input	current	IN from O V/ to V/				10	^
I _{IL}	Low-level input of	ow-level input current IN from 0 V to V _{CC}		-10			μΑ	
Cı	Input capacitanc	e to ground	IN at V_{CC} , $V_{I} = 0.4 \sin (4E6\pi t)$			2		pF
CMTI	Common-mode immunity	transient	V _I = V _{CC} or 0 V, See Figure 4		25	50		kV/μs

⁽¹⁾ For the 5-V operation, V_{CC1} or V_{CC2} is specified from 4.5 V to 5.5 V. For the 3-V operation, V_{CC1} or V_{CC2} is specified from 3.15 V to 3.6 V.



SWITCHING CHARACTERISTICS: V_{CC1} at 3.3-V and V_{CC2} at 5-V OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH} , t _{PHL}	Propagation delay	100700 0		22		51	
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} - t _{PLH}	ISO723xC				3	
t _{PLH} , t _{PHL}	Propagation delay	100700 14	See Figure 1	12		30	ns
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} - t _{PLH}	ISO723xM	723XM		1	2	
4	Dort to nort alsour (2)	ISO723xC				10	
t _{sk(pp)}	Part-to-part skew ⁽²⁾	ISO723xM			0	5	ns
	Channel to abannel autout alray (3)	ISO723xC			0	2.5	
t _{sk(o)}	Channel-to-channel output skew (3)	ISO723xM			0	1	ns
t _r	Output signal rise time	•	Con Figure 4		2		
t _f	Output signal fall time		See Figure 1		2		ns
t _{PHZ}	Propagation delay, high-level-to-high-impedance	ce output			15	20	
t _{PZH}	Propagation delay, high-impedance-to-high-lev	el output	See Figure 2		15	20	
t _{PLZ}	Propagation delay, low-level-to-high-impedance	e output	See Figure 2		15	20	ns
t _{PZL}	Propagation delay, high-impedance-to-low-level output				15	20	
t _{fs}	Failsafe output delay time from input power loss		See Figure 3		12		μS
t _{jit(pp)}	Peak-to-peak eye-pattern jitter	ISO723xM	150 Mbps PRBS NRZ data input, Same polarity input on all channels, See Figure 5		1		ns

Also known as pulse skew

t_{sk(pp)} is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices (2)

operate with the same supply voltages, at the same temperature, and have identical packages and test circuits. $t_{sk(0)}$ is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.



ELECTRICAL CHARACTERISTICS: V_{CC1} and V_{CC2} at 3.3 $V^{(1)}$ OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
SUPPLY	CURRENT			<u> </u>		'	
	10070000/M	Quiescent	V _I = V _{CC} or 0 V, all channels, no load,		0.5	1	^
	ISO7230C/M	25 Mbps	EN ₂ at 3 V		3	5	mA
I _{CC1}	10070040/M	Quiescent	V _I = V _{CC} or 0 V, all channels, no load,		4.5	7	^
	ISO7231C/M	25 Mbps	EN ₁ at 3 V, EN ₂ at 3 V		6.5	11	mA
	10070000/M	Quiescent	V _I = V _{CC} or 0 V, all channels, no load,		9	15	^
	ISO7230C/M	25 Mbps	EN ₂ at 3 V		10	17	mA
I _{CC2}	10070040/M	Quiescent	V _I = V _{CC} or 0 V, all channels, no load,		8	12	^
	ISO7231C/M	25 Mbps	EN ₁ at 3 V, EN ₂ at 3 V		10.5	16	mA
ELECTR	RICAL CHARACTERISTICS	•					
I _{OFF}	Sleep mode output current		EN at 0 V, single channel		0		μА
V	High-level output voltage		I _{OH} = -4 mA, See Figure 1	V _{CC} - 0.4	V _{CC} - 0.4		V
V _{OH}	nigh-level output voltage		$I_{OH} = -20 \mu A$, See Figure 1	V _{CC} - 0.1			V
\/	Low-level output voltage		I _{OL} = 4 mA, See Figure 1			0.4	V
V _{OL}	Low-level output voltage		I_{OL} = 20 μ A, See Figure 1			0.1	v
$V_{I(HYS)}$	Input voltage hysteresis				150		mV
I _{IH}	High-level input current		INI from O.V. or V.			10	^
I _{IL}	Low-level input current		IN from 0 V or V _{CC}	-10			μА
Cı	Input capacitance to ground		IN at V_{CC} , $V_I = 0.4 \sin (4E6\pi t)$		2		pF
CMTI	Common-mode transient im	munity	V _I = V _{CC} or 0 V, See Figure 4	25	50		kV/μs

⁽¹⁾ For the 5-V operation, V_{CC1} or V_{CC2} is specified from 4.5 V to 5.5 V. For the 3-V operation, V_{CC1} or V_{CC2} is specified from 3.15 V to 3.6 V.



SWITCHING CHARACTERISTICS: V_{CC1} and V_{CC2} at 3.3-V OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH} , t _{PHL}	Propagation delay	1007000	Con Figure 4	25		56	
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} - t _{PLH}	ISO723xC	See Figure 1			4	ns
t _{pLH} , t _{pHL}	Propagation delay	10070014		12		34	
PWD	Pulse-width distortion ⁽¹⁾ t _{PHL} - t _{PLH}	ISO723xM			1	2	ns
4	Part-to-part skew (2)	ISO723xC				10	
t _{sk(pp)}	Part-to-part skew V	ISO723xM			0	5	ns
4	Channel-to-channel output skew (3)	ISO723xC			0	3	
t _{sk(o)}	Channel-to-channel output skew	ISO723xM			0	1	ns
t _r	Output signal rise time		See Figure 1		2		
t _f	Output signal fall time				2		ns
t _{PHZ}	Propagation delay, high-level-to-high-imp	pedance output			15	20	
t _{PZH}	Propagation delay, high-impedance-to-h	igh-level output	See Figure 2		15	20	ns
t _{PLZ}	Propagation delay, low-level-to-high-imp	edance output	See Figure 2		15	20	115
t _{PZL}	Propagation delay, high-impedance-to-low-level output				15	20	
t _{fs}	Failsafe output delay time from input power loss		See Figure 3		18		μS
t _{jit(pp)}	Peak-to-peak eye-pattern jitter	ISO723xM	150 Mbps PRBS NRZ data input, same polarity input on all channels, See Figure 5		1		ns

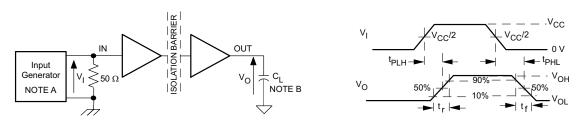
⁽¹⁾ Also referred to as pulse skew.

⁽²⁾ t_{sk(pp)} is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

⁽³⁾ $t_{sk(0)}$ is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.

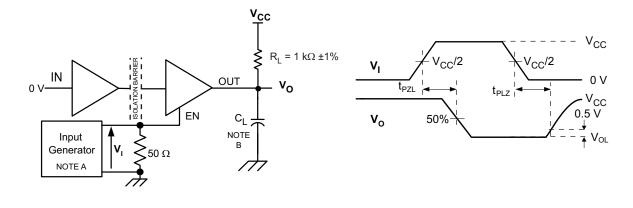


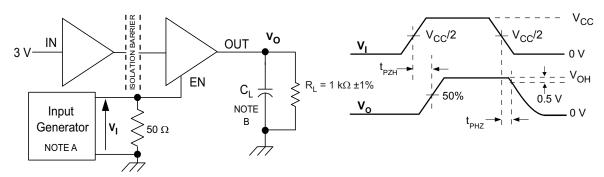
PARAMETER MEASUREMENT INFORMATION



- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 50 kHz, 50% duty cycle, $t_r \leq$ 3 ns, $t_f \leq$ 3 ns, $Z_O = 50\Omega$.
- B. $C_L = 15$ pF and includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 1. Switching Characteristic Test Circuit and Voltage Waveforms



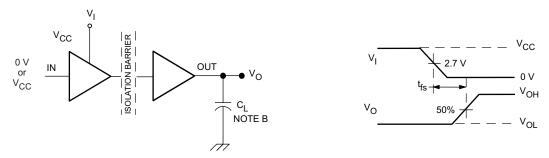


- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 50 kHz, 50% duty cycle, $t_r \leq$ 3 ns, $t_f \leq$ 3 ns, $Z_O = 50\Omega$.
- B. $C_L = 15$ pF and includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 2. Enable/Disable Propagation Delay Time Test Circuit and Waveform

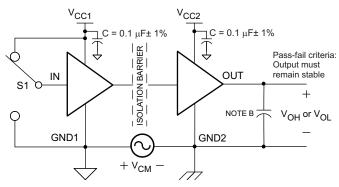


PARAMETER MEASUREMENT INFORMATION (continued)



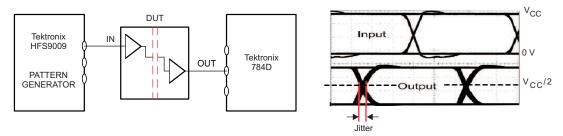
- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 50 kHz, 50% duty cycle, $t_r \leq$ 3 ns, $t_f \leq$ 3 ns, $Z_O = 50\Omega$.
- B. $C_L = 15 \text{ pF}$ and includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 3. Failsafe Delay Time Test Circuit and Voltage Waveforms



- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 50 kHz, 50% duty cycle, $t_r \leq$ 3 ns, $t_f \leq$ 3 ns, $Z_O = 50\Omega$.
- B. $C_L = 15$ pF and includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 4. Common-Mode Transient Immunity Test Circuit and Voltage Waveform



NOTE: PRBS bit pattern run length is 2¹⁶ – 1. Transition time is 800 ps. NRZ data input has no more than five consecutive 1s or 0s.

Figure 5. Peak-to-Peak Eye-Pattern Jitter Test Circuit and Voltage Waveform



DEVICE INFORMATION

PACKAGE CHARACTERISTICS

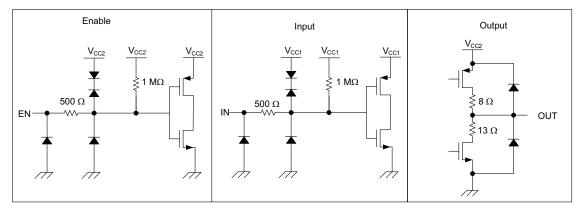
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
L(101)	Minimum air gap (Clearance)	Shortest terminal-to-terminal distance through air	8.34			mm
L(102)	Minimum external tracking (Creepage)	Shortest terminal-to-terminal distance across the package surface	8.1		mm	
	Minimum Internal Gap (Internal Clearance)	Distance through the insulation	0.008			mm
R _{IO}	Isolation resistance	Input to output, V_{IO} = 500 V, all pins on each side of the barrier tied together creating a two-terminal device, T_A < 100°C	e >10 ¹²			Ω
		Input to output, $V_{IO} = 500 \text{ V}$, $100^{\circ}\text{C} \le T_{A} \le T_{A} \text{ max}$		>10 ¹¹		Ω
C_{IO}	Barrier capacitance Input to output	$V_1 = 0.4 \sin (4E6\pi t)$		2		pF
Cı	Input capacitance to ground	$V_1 = 0.4 \sin (4E6\pi t)$		2		pF

REGULATORY INFORMATION

VDE	CSA	UL
Certified according to IEC 60747-5-2	Approved under CSA Component Acceptance Notice	Recognized under 1577 Component Recognition Program ⁽¹⁾
File Number: 40016131	File Number: 220991	File Number: E181974

⁽¹⁾ Production tested ≥ 3000 VRMS for 1 second in accordance with UL 1577.

DEVICE I/O SCHEMATICS



NOTE: Input is assumed to be on $\rm V_{\rm CC1}$ side and Output on $\rm V_{\rm CC2}$ side.

THERMAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
0	Junction-to-air	Low-K Thermal Resistance ⁽¹⁾	168			°C/W
θ_{JA}		High-K Thermal Resistance	96.1			C/VV
θ_{JB}	Junction-to-Board Thermal Resistance			61		°C/W
θ_{JC}	Junction-to-Case Thermal Resistance			48		°C/W
P_{D}	Device Power Dissipation	$V_{CC1} = V_{CC2} = 5.5 \text{ V}, T_J = 150^{\circ}\text{C}, C_L = 15 \text{ pF},$ Input a 50% duty cycle square wave			220	mW

(1) Tested in accordance with the Low-K or High-K thermal metric definitions of EIA/JESD51-3 for leaded surface mount packages.

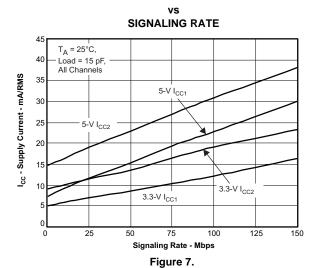


TYPICAL CHARACTERISTIC CURVES

ISO7230 C/M RMS SUPPLY CURRENT

SIGNALING RATE 45 T_A = 25°C, Load = 15 pF, 40 All Channels I_{CC} - Supply Current - mA/RMS 35 30 5-V I_{CC2} 3.3-V I_{CC2} 25 3.3-V I_{CC1} 125 100 150 75 Signaling Rate - Mbps

ISO7231 C/M RMS SUPPLY CURRENT



PROPAGATION DELAY

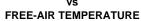


Figure 6.

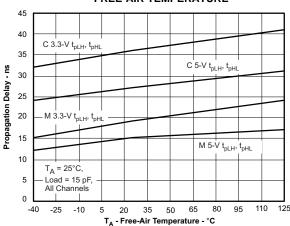


Figure 8.

INPUT THRESHOLD VOLTAGE



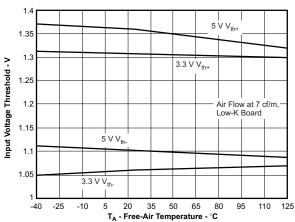


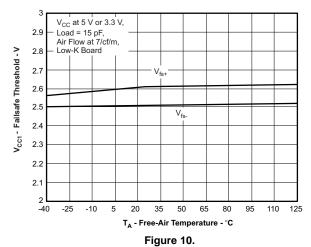
Figure 9.



TYPICAL CHARACTERISTIC CURVES (continued)

V_{CC1} FAILSAFE THRESHOLD

FREE-AIR TEMPERATURE



HIGH-LEVEL OUTPUT CURRENT

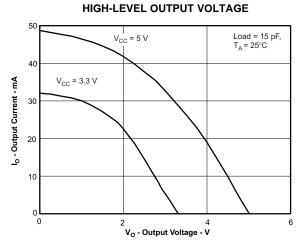
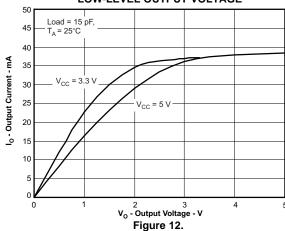


Figure 11.

LOW-LEVEL OUTPUT CURRENT

LOW-LEVEL OUTPUT VOLTAGE





APPLICATION INFORMATION

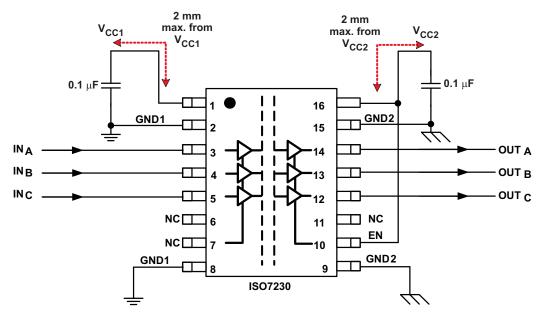


Figure 13. Typical ISO7230 Application Circuit

LIFE EXPECTANCY vs WORKING VOLTAGE

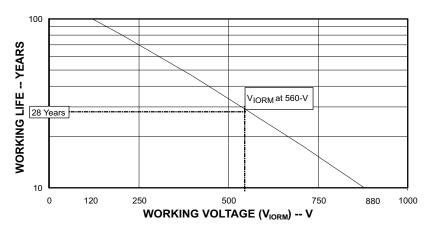


Figure 14. Time Dependant Dielectric Breakdown Testing Results



REVISION HISTORY

Cł	nanges from Original (September 2007) to Revision A	Page
•	Deleted Product Preview note	2
•	Changed V _{CC} Supply Voltage of the ROC Table From: 3 To: 3.15	3
•	Changed From: 3.6 To: 3.45	3
•	Changed TBD to actual values	4
•	Changed V _{CC} – 0.4 To: V _{CC} – 0.8	4
•	Changed C ₁ - Typical value from 1 To: 2	
•	Changed Propagation delay max From: 22 To: 23	5
•	Changed C ₁ - Typical value from 1 To: 2	6
•	Changed Propagation delay max From: 46 To: 50	7
•	Changed Propagation delay max From: 28 To: 29	7
•	Changed C ₁ - Typical value from 1 To: 2	8
•	Changed Propagation delay max From: 26 To: 30	9
•	Changed C _I - Typical value from 1 To: 2	10
•	Changed Propagation delay max From: 32 To: 34	11
•	Changed C _{IO} - Typical value from 1 To: 2	14
•	Changed C _I - Typical value from 1 To: 2	14
•	Changed the REGULATORY INFORMATION Table	14
•	Changed Figure 6, Figure 7, and Figure 8	15
Cŀ	nanges from Revision A (December 2007) to Revision B	Page
•	Changed Supply Voltage of the ROC Table From: 3.45 To: 3.6	3
Cŀ	nanges from Revision B (April 2008) to Revision C	Page
•	Deleted Min = 4.5 V and max = 5.5 V for Supply Voltage of the ROC Table.	3
<u>. </u>	Changed Supply Voltage of the ROC Table From: 3.6 To: 5.5	3
Cŀ	nanges from Revision C (April 2008) to Revision D	Page
•	Changed Features bullet 4000-V _{peak} Isolation to the Features list	1
•	Added t _{sk(pp)} Part-to-part skew	5
•	Added t _{sk(pp)} Part-to-part skew	7
•	Added t _{sk(pp)} Part-to-part skew	9
•	Added t _{sk(pp)} Part-to-part skew	11
•	Changed Typical ISO723x Application Circuit Figure 13	17



Cł	nanges from Revision D (May 2008) to Revision E	Page
•	Added Note: For the 5-V operation, VCC1 or VCC2 is specified from 4.5 V to 5.5 V. For the 3-V operation, VCC1 or VCC2 is specified from 3.15 V to 3.6 V.	
•	Added Note: For the 5-V operation, VCC1 or VCC2 is specified from 4.5 V to 5.5 V. For the 3-V operation, VCC1 or VCC2 is specified from 3.15 V to 3.6 V.	
•	Added Note: For the 5-V operation, VCC1 or VCC2 is specified from 4.5 V to 5.5 V. For the 3-V operation, VCC1 or VCC2 is specified from 3.15 V to 3.6 V.	
•	Added Note: For the 5-V operation, VCC1 or VCC2 is specified from 4.5 V to 5.5 V. For the 3-V operation, VCC1 or VCC2 is specified from 3.15 V to 3.6 V.	
•	Added Note: For the 5-V operation, VCC1 or VCC2 is specified from 4.5 V to 5.5 V. For the 3-V operation, VCC1 or VCC2 is specified from 3.15 V to 3.6 V.	
Cł	nanges from Revision E (June 2008) to Revision F	Page
	Deleted device numbers ISO7230A and ISO7231A from the data sheet.	1
•	Deleted text from the Description "and turns off internal bias circuitry to conserve power"	1
•	Added t _{sk(pp)} footnote.	5
•	Added t _{sk(o)} footnote.	5
•	Added t _{sk(pp)} footnote.	11
•	Added t _{sk(o)} footnote.	11
<u>.</u>	Changed the PACKAGE CHARACTERISTICS table, line 1, L _(IO1) MIN from 7.7 to 8.34	14
Cł	nanges from Revision F (December 2008) to Revision G	Page
•	Added IEC 60950-1 and CSA Approved to the Features list	1
Cł	nanges from Revision G (September 2009) to Revision H	Page
<u>.</u>	Changed The Input circuit in the DEVICE I/O SCHEMATICS illustration	14
Cł	nanges from Revision H (December 2009) to Revision I	Page
•	Changed I _{OH} Min value to -4 and deleted the Max value, in the RECOMMENDED OPERATING CONDITIONS Table	e 3
•	Changed I_{OL} Max value to 4 and deleted the Min value, in the RECOMMENDED OPERATING CONDITIONS Table	3
•	Changed Figure 1, Figure 3, Figure 4, and Figure 5	12
•	Changed File Number: 1698195 To: 220991	14
•	Changed Typical ISO723x Application Circuit Figure 13	17
_		

PACKAGE OPTION ADDENDUM



11-Apr-2013

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Top-Side Markings	Samples
ISO7230CDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7230C	Samples
ISO7230CDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7230C	Samples
ISO7230CDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7230C	Sample
ISO7230CDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7230C	Sample
ISO7230MDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7230M	Sample
ISO7230MDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7230M	Sample
ISO7230MDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7230M	Sample
ISO7230MDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7230M	Sample
ISO7231CDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7231C	Sample
ISO7231CDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7231C	Sample
ISO7231CDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	ISO7231C	Sample
ISO7231CDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	ISO7231C	Sample
ISO7231MDW	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7231M	Sample
ISO7231MDWG4	ACTIVE	SOIC	DW	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7231M	Sample
ISO7231MDWR	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7231M	Sample
ISO7231MDWRG4	ACTIVE	SOIC	DW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	ISO7231M	Sample

⁽¹⁾ The marketing status values are defined as follows: **ACTIVE:** Product device recommended for new designs.



PACKAGE OPTION ADDENDUM

11-Apr-2013

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) Multiple Top-Side Markings will be inside parentheses. Only one Top-Side Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Top-Side Marking for that device.

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OTHER QUALIFIED VERSIONS OF ISO7231C:

Automotive: ISO7231C-Q1

NOTE: Qualified Version Definitions:

Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

PACKAGE MATERIALS INFORMATION

www.ti.com 14-Sep-2013

TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ISO7230CDWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1
ISO7231MDWR	SOIC	DW	16	2000	330.0	16.4	10.75	10.7	2.7	12.0	16.0	Q1

PACKAGE MATERIALS INFORMATION

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*All dimensions are nominal

ĺ	Device	Package Type Package Drawing		Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
I	ISO7230CDWR	SOIC	DW	16	2000	367.0	367.0	38.0	
I	ISO7231MDWR	SOIC	DW	16	2000	367.0	367.0	38.0	

DW (R-PDSO-G16)

PLASTIC SMALL OUTLINE



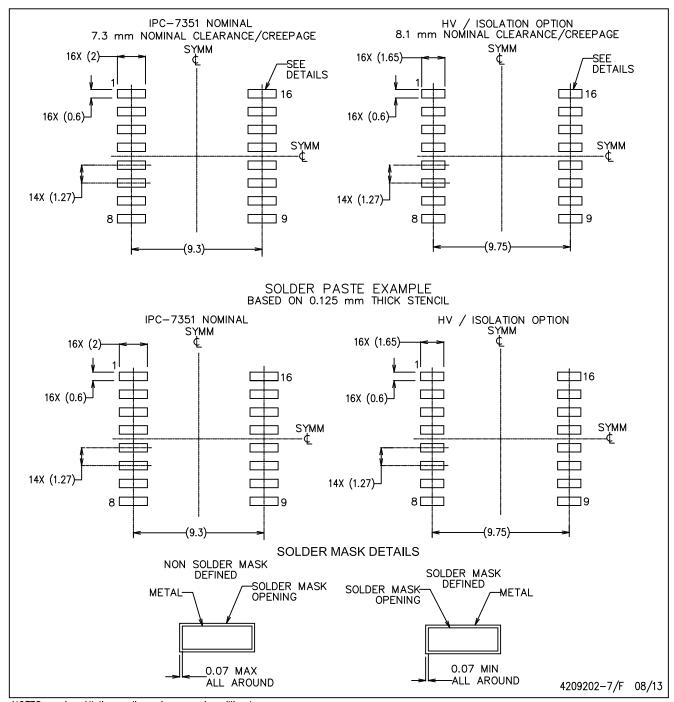
NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AA.



DW (R-PDSO-G16)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Refer to IPC7351 for alternate board design.
- D. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
- E. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- F. Board assembly site may have different recommendations for stencil design.



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